

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
S1	14	"4,857,731"	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/07/31 12:24
S2	9	"5,801382"	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/07/31 12:24
S3	460289	Inspection or metrology same semiconductors	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/07/31 12:37
S4	26711	S3 and (characteristic near4 x-rays or emissions)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/07/31 12:36
S5	5257	S4 and (cavity or hole near4 inspection)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/07/31 12:28
S6	671	S5 and (electron near4 beam)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/07/31 12:27
S7	671	S6 and (characteristic near4 x-rays or emissions)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/07/31 12:27

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S8	637	S7 and (cavity or hole near4 material)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/07/31 12:36
S9	594	S7 and (cavity or hole near4 x-ray adj inspection)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/07/31 12:29
S10	392	S7 and (first adj portion near4 cavity or hole)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/07/31 12:36
S11	315	S10 and (cavity or hole near4 overlap\$3)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/07/31 12:31
S12	0	S10 and (inspect\$3 near4 first adj portion)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/07/31 12:32
S13	0	S11 and (inspect\$3 near4 first adj portion)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/07/31 12:32
S14	8	S11 and (inspect\$3 near4 portion)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/07/31 12:37

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S15	10650	(250/307,310,306,305,492.2,492.1,). CCLS.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/07/31 12:36
S16	2722	S15 and (characteristic near4 x-rays or emissions)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/07/31 12:36
S17	305	S16 and (cavity or hole near4 material)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/07/31 12:36
S18	190	S17 and (first adj portion near4 cavity or hole)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/07/31 12:36
S19	12	S18 and (inspect\$3 near4 portion)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/07/31 12:37
S20	0	(Inspection or metrology same semiconductors) and (electron near4 beam) and (characteristics near4 x-rays or emissions) and (cavity or hole near4 inspection) and (first adj portion near4 cavity or hole) and (inspect\$3 near4 first adj portion).clm.	US-PGPUB; USPAT	AND	ON	2007/07/31 12:41
S21	19	shemesh-drdr.IN.	US-PGPUB; USPAT	AND	ON	2007/07/31 12:41